

Test report No.

: 28IE0193-HO-02-A-R2

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Issued date Revised date : July 22, 2008 : August 20, 2008

FCC ID

: WAZX1T805SKE11A03

RADIO TEST REPORT

Test Report No.: 28IE0193-HO-02-A-R2

Applicant

Mitsubishi Electric Corporation Himeji Works

Type of Equipment

SMART KEYLESS SYSTEM (Smart ECU)

Model No.

SKE11A-03

Test regulation

FCC Part 15 Subpart C: 2008

Section 15.207 and 15.209

FCC ID

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WAZX1T805SKE11A03

Test Result

Complied

- 1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
- 2. The results in this report apply only to the sample tested.
- 3. This sample tested is in compliance with above regulation.
- 4. The test results in this report are traceable to the national or international standards.
- 5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
- 6. Original test report number of this report is 28IE0193-HO-02-A.

Date of test:

July 7 and 9, 2008

Tested by:

Takahiro Hatakeda EMC Services Hisayoshi Sato EMC Services

Approved by:

Makoto Kosaka EMC Services



NVLAP LAB CODE: 200572-0

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*As for the range of Accreditation in NVLAP, you may refer to the WEB address, http://uljapan.co.jp/emc/nvlap.htm

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SECTION 1: Customer information

Company Name : Mitsubishi Electric Corporation Himeji Works Address : 840 Chiyoda-machi Himeji Hyogo 670-8677 Japan

Telephone Number : +81-792-98-8896 Facsimile Number : +81-792-98-9262 Contact Person : Yoshiharu Goto

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : SMART KEYLESS SYSTEM (Smart ECU)

 Model No.
 :
 SKE11A-03

 Sample No.
 :
 20080624-01

 Rating
 :
 DC 12.0V

 Receipt Date of Sample
 :
 May 15, 2008

Country of Mass-production : Japan

Condition of EUT : Production prototype

(Not for Sale: This sample is equivalent to mass-produced items.)

Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: SKE11A-03 (referred to as the EUT in this report) is the SMART KEYLESS SYSTEM (Smart ECU).

Clock frequencies : 10MHz

Frequency of Operation : 133.33kHz
Type of modulation : PPM
Antenna Type : Bar Antenna
Method of Frequency Generation : Crystal
Operating Voltage (Inner) : DC 5V

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2008, , final revised on May 19, 2008
Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional

Radiators

Section 15.207 Conducted Emission

Section 15.209 Radiated emission limits, general requirements

FCC 15.31 (e)

The EUT is a battery-operated device and test was performed with the full-charged battery.

The power supply of this EUT is transformed to DC 5.0V and provides stable voltage (DC5.0V) constantly to Radio part. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the vehicle. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.2 Procedures and results

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	Conducted Emission	<fcc> ANSI C63.4:2003 7. AC powerline conducted emission measurements <ic> RSS-Gen 7.2.2</ic></fcc>	<fcc> Section 15.207 <ic> RSS-Gen 7.2.2</ic></fcc>	-	N/A *1)	N/A	N/A
2	Electric Field Strength of Fundamental Emission	<fcc> ANSI C63.4:2003 13. Measurement of intentional radiators <ic> RSS-Gen 4.8, 4.11</ic></fcc>	<fcc> Section 15.209 <ic> RSS-210 2.6, 2.7</ic></fcc>	Radiated	N/A	18.1dB 0.13333MHz 0 deg. AV (Antenna C(Full))	Complied
	Electric Field Strength of Spurious Emission	<fcc> ANSI C63.4:2003 13. Measurement of intentional radiators <ic> RSS-Gen 4.9, 4.11</ic></fcc>	<fcc> Section 15.209 <ic> RSS-210 2.6, 2.7</ic></fcc>	Radiated	N/A	8.2dB 61.881MHz, Horizontal (Antenna G(Full))	Complied
4	-26dB Bandwidth	<fcc> ANSI C63.4:2003 13. Measurement of intentional radiators <ic></ic></fcc>	<fcc> Reference data <ic> -</ic></fcc>	Radiated	N/A	N/A	N/A

Note: UL Japan, Inc.'s EMI Work Procedures No.QPM05 and QPM15.

3.3 Addition to standards

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied	RSS-Gen 4.6.1	RSS-Gen 4.6.1	Radiated	N/A	N/A	N/A
	Band Width						

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^{*1)} The test is not applicable since the EUT is not the device that is designed to be connected to the public utility (AC) power line.

^{*}These tests were performed without any deviations from test procedure except for additions or exclusions.

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3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

	Conducted	Radiated emission		Radiated emission			Radi	ated	
Test room	emission	(10m*)		(3m*)			emission (3m*)		
100010011	150kHz- 30MHz	9kHz- 30MHz	30MHz- 300MHz	300MHz- 1GHz	9kHz- 30MHz	30MHz- 300MHz	300MHz- 1GHz	1GHz- 18GHz	18GHz- 40GHz
No.1 semi-anechoic Chamber (±)	3.7dB	3.1dB	4.4dB	4.2dB	3.2dB	3.8dB	3.9dB	5.9dB	6.1dB
No.2 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.4dB	4.0dB	5.9dB	6.1dB
No.3 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.6dB	4.0dB	5.9dB	6.1dB
No.4 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	3.9dB	3.9dB	5.9dB	6.1dB

^{*10}m/3m = Measurement distance

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

Other test except Conducted Emission and Spurious Emission (Radiated)

The measurement uncertainty for this test is ± 3.0 dB.

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3.5 Test Location

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	FCC	IC Registration	Width x Depth x	Size of	Other
	Registration Number	Number	Height (m)	reference ground plane (m) / horizontal conducting plane	rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

^{*} Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Test instruments and Data of EMI

Refer to APPENDIX 1 to 3.

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SECTION 4: Operation of E.U.T. during testing

4.1 Operating Modes

The mode is used: 1) Continuous Transmitting 133.33kHz mode (Full)

2) Continuous Transmitting 133.33kHz mode (Half)

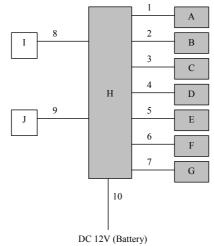
The output power level can be switched from (Full) to (Half) by Jig.

The tests were performed with both output power level. *Please refer to Appendix 4 for data of pulse line.

Justification : The system was configured in typical fashion (as a customer would normally use it)

for testing.

4.2 Configuration and peripherals



* Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remark
A	Antenna A	SKE11A-03	20080509-01	Mitsubishi Electric Corporation	EUT
				Himeji Works	
В	Antenna B	SKE11A-03	20080509-01	Mitsubishi Electric Corporation	EUT
				Himeji Works	
C	Antenna C	SKE11A-03	20080509-01	Mitsubishi Electric Corporation	EUT
				Himeji Works	
D	Antenna D	SKE11A-03	20080509-01	Mitsubishi Electric Corporation	EUT
				Himeji Works	
Е	Antenna E	SKE11A-03	20080509-01	Mitsubishi Electric Corporation	EUT
				Himeji Works	
F	Antenna F	SKE11A-03	20080509-01	Mitsubishi Electric Corporation	EUT
				Himeji Works	
G	Antenna G	SKE11A-03	20080509-01	Mitsubishi Electric Corporation	EUT
				Himeji Works	
Н	SMART KEYLESS SYSTEM	SKE11A-03	20080624-01	Mitsubishi Electric Corporation	EUT
	(Smart ECU)			Himeji Works	
I	SMART KEYLESS SYSTEM	SKE11A-03	20080512-R1	Mitsubishi Electric Corporation	-
	(Receiver)			Himeji Works	
J	Jig	-	-	Mitsubishi Electric Corporation	-
				Himeji Works	

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List of cables used

No.	Name	Length (m)	SI	Remark	
			Cable	Connector	
1	Antenna Cable	1.5	Unshielded	Unshielded	-
2	Antenna Cable	1.5	Unshielded	Unshielded	-
3	Antenna Cable	1.4	Unshielded	Unshielded	-
4	Antenna Cable	1.4	Unshielded	Unshielded	*1)
5	Antenna Cable	1.4	Unshielded	Unshielded	*1)
6	Antenna Cable	1.4	Unshielded	Unshielded	*1)
7	Antenna Cable	1.4	Unshielded	Unshielded	*1)
8	Signal & DC cable	1.3	Unshielded	Unshielded	-
9	Signal & DC cable	1.4	Unshielded	Unshielded	-
10	DC Cable	1.2	Unshielded	Unshielded	-

^{*1) 1.25}m out of 1.4m have been shielded.

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SECTION 5: Radiated emission (Fundamental and Spurious Emission)

Test Procedure

The Radiated Electric Field Strength intensity has been measured on No.3 semi anechoic chamber with a ground plane and at a distance of 3m.

Frequency: From 9kHz to 30MHz at distance 3m

The EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for each antenna angle 0deg., 45deg. and 90deg.

Frequency: From 30MHz to 1GHz at distance 3m

The measuring antenna height varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization.

Measurements were performed with a QP, PK, and AV detector.

The radiated emission measurements were made with the following detector function of the test receiver (below 1GHz) and the spectrum analyzer (above 1GHz).

	From 9kHz to 90kHz	From	From	From	From
	and	90kHz to	150kHz	490kHz to	30MHz to
	From 110kHz to	110kHz	to 490kHz	30MHz	1GHz
	150kHz				
Detector Type	PK/AV	QP	PK/AV	QP	QP
IF Bandwidth	200Hz	200Hz	9kHz	9kHz	120kHz

⁻ The carrier level (or, noise levels) was (or were) measured at each position of all three axes X, Y and Z, and the position that has the maximum noise was determined.

With the position, the noise levels of all the frequencies were measured.

* Part 15 Section 15.31 (f)(2) (9kHz-30MHz)

[Limit at 3m]=[Limit at 300m]- $40 \times \log (3[m]/300[m])$

[Limit at 3m]=[Limit at 30m]- $40 \times \log (3[m]/30[m])$

Test data : APPENDIX 3

Test result : Pass

Date: July 7 and 9, 2008 Test engineer: Takahiro Hatakeda and Hisayoshi Sato

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SECTION 6: -26dB Bandwidth

Test Procedure

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Test data : APPENDIX 2

Test result : Pass

SECTION 7: 99% Occupied Bandwidth

Test Procedure

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Test data : APPENDIX 2

Test result : Pass

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